

ABSTRACT

PROBE CARD

5 A probe card includes probes that come into contact
with a semiconductor wafer to receive or output an electric
signal; a probe head that holds the probes; a substrate
that has a wiring pattern corresponding to a circuit
structure for generating a signal for a test; a reinforcing
10 member that reinforces the substrate; an interposer that is
stacked on the substrate and includes a housing having
connection terminals resilient in an axial direction
thereof and hole portions each housing one of the
connection terminals; and a space transformer that is
15 stacked between the interposer and the probe head and
transforms intervals among the wires.

Fig. 3